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TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor SCHS055

January 1998

Features

- High-Voltage Types (20V Rating)
- CD4070B Quad Exclusive-OR Gate
- CD4077B Quad Exclusive-NOR Gate
- Medium Speed Operation
 - t_{PHL} , t_{PLH} = 65ns (Typ) at V_{DD} = 10V, C_L = 50pF
- 100% Tested for Quiescent Current at 20V
- Standardized Symmetrical Output Characteristics
- 5V, 10V and 15V Parametric Ratings
- Maximum Input Current of $1\mu\text{A}$ at 18V Over Full Package Temperature Range
 - 100nA at 18V and 25°C
- Noise Margin (Over Full Package Temperature Range)
 1V at V_{DD} = 5V, 2V at V_{DD} = 10V, 2.5V at V_{DD} = 15V
- Meets All Requirements of JEDEC Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices

Applications

- Logical Comparators
- Adders/Subtractors
- Parity Generators and Checkers

CD4070B, CD4077B

CMOS Quad Exclusive-OR and Exclusive-NOR Gate

Description

The Harris CD4070B contains four independent Exclusive-OR gates. The Harris CD4077B contains four independent Exclusive-NOR gates.

The CD4070B and CD4077B provide the system designer with a means for direct implementation of the Exclusive-OR and Exclusive-NOR functions, respectively.

Ordering Information

PART NUMBER	TEMP. RANGE (^O C)	PACKAGE	PKG. NO.
CD4070BE	-55 to 125	14 Ld PDIP	E14.3
CD4077BE	-55 to 125	14 Ld PDIP	E14.3
CD4070BF	-55 to 125	14 Ld CERDIP	F14.3
CD4077BF	-55 to 125	14 Ld CERDIP	F14.3
CD4070BM	-55 to 125	14 Ld SOIC	M14.15
CD4077BM	-55 to 125	14 Ld SOIC	M14.15





CD4070B TRUTH TABLE (1 OF 4 GATES)

A	В	J
0	0	0
1	0	1
0	1	1
1	1	0

NOTE:

1 = High Level

0 = Low Level

 $J = A \oplus B$



CD4077B TRUTH TABLE (1 OF 4 GATES)

Α	В	J
0	0	1
1	0	0
0	1	0
1	1	1

NOTE:

1 = High Level

0 = Low Level

 $J = \overline{A \oplus B}$

Absolute Maximum Ratings

DC Supply Voltage Range (V _{DD})	-0.5V to 20V
Input Voltage Range, All Inputs0.5V	′ to V _{DD} 0.5V
DC Input Current	±10mA

Operating Conditions

Temperature Range (T _A)	55°C to 125°C
Supply Voltage Range (Typical)	\ldots 3V to 18V

Thermal Information

Thermal Resistance (Typical, Note 1)	θ _{JA} (^o C/W)	θ _{JC} (^o C/W)
PDIP Package	90	N/A
CERDIP Package	95	38
SOIC Package	175	N/A
Maximum Junction Temperature (Hermetic I	Package or Di	e)175 ⁰ C
Maximum Junction Temperature (Plastic F	Package)	150 ⁰ C
Maximum Storage Temperature Range	65	5 ^o C to 150 ^o C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

				LIMITS AT INDICATED TEMPERATURES (°C)							
	COI	DITION	S					25			
PARAMETER	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	85	125	MIN	түр	МАХ	UNITS
Quiescent Device Current	-	0, 5	5	0.25	0.25	7.5	7.5	-	0.01	0.25	μΑ
IDD Max	-	0, 10	10	0.5	0.5	15	15	-	0.01	0.5	μΑ
	-	0, 15	15	1	1	30	30	-	0.01	1	μΑ
	-	0, 20	20	5	5	150	150	-	0.02	5	μΑ
Output Low (Sink) Current	0.4	0, 5	5	0.64	0.61	0.42	0.36	0.51	1	-	mA
	0.5	0, 10	10	1.6	1.5	1.1	0.9	1.3	2.6	-	mA
	1.5	0, 15	15	4.2	4	2.8	2.4	3.4	6.8	-	mA
Output High (Source) Current	4.6	0, 5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	-	mA
I _{OH} Min	2.5	0, 5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-	mA
	9.5	0, 10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	-	mA
	13.5	0, 15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	-	mA
Output Voltage: Low Level,	-	0, 5	5	0.05	0.05	0.05	0.05	-	0	0.05	V
	-	0, 10	10	0.05	0.05	0.05	0.05	-	0	0.05	V
	-	0, 15	15	0.05	0.05	0.05	0.05	-	0	0.05	V
Output Voltage: High Level,	-	0, 5	5	4.95	4.95	4.95	4.95	4.95	5	-	V
VOH MIN	-	0, 10	10	9.95	9.95	9.95	9.95	9.95	10	-	V
	-	0, 15	15	14.95	14.95	14.95	14.95	14.95	15	-	V
Input Low Voltage,	0.5, 4.5	-	5	1.5	1.5	1.5	1.5	-	-	1.5	V
	1, 9	-	10	3	3	3	3	-	-	3	V
	1.5, 13.5	-	15	4	4	4	4	-	-	4	V
Input High Voltage,	0.5, 4.5	-	5	3.5	3.5	3.5	3.5	3.5	-	-	V
VIH Min	1, 9	-	10	7	7	7	7	7	-	-	V
	1.5, 13.5	-	15	11	11	11	11	11	-	-	V
Input Current, I _{IN} Max	-	0, 18	18	±0.1	±0.1	±1	±1	-	±10 ⁻⁵	±0.1	μΑ

AC Electrical Specifications $T_A = 25^{\circ}C$, Input t_r , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω								
		TEST CONDITIONS	LIMITS ON ALL TYPES					
PARAMETER	SYMBOL	V _{DD} (V)	ТҮР	МАХ	UNITS			
Propagation Delay Time	t _{PHL} , t _{PLH}	5	140	280	ns			
		10	65	130	ns			
		15	50	100	ns			
Transition Time	t _{THL} , t _{TLH}	5	100	200	ns			
		10	50	100	ns			
		15	40	80	ns			
Input Capacitance	C _{IN}	Any Input	5	7.5	pF			

Typical Performance Curves



FIGURE 3. TYPICAL OUTPUT LOW (SINK) CURRENT CHARACTERISTICS



FIGURE 5. TYPICAL OUTPUT HIGH (SOURCE) CURRENT CHARACTERISTICS















FIGURE 9. TYPICAL PROPAGATION DELAY TIME AS A FUNCTION OF SUPPLY VOLTAGE







FIGURE 10. TYPICAL DYNAMIC POWER DISSIPATION AS A FUNCTION OF INPUT FREQUENCY

Dual-In-Line Plastic Packages (PDIP)



NOTES:

- 1. Controlling Dimensions: INCH. In case of conflict between English and Metric dimensions, the inch dimensions control.
- 2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
- 3. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication No. 95.
- 4. Dimensions A, A1 and L are measured with the package seated in JEDEC seating plane gauge GS-3.
- 5. D, D1, and E1 dimensions do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.010 inch (0.25mm).
- 6. E and $\boxed{e_A}$ are measured with the leads constrained to be perpendicular to datum $\boxed{-C_-}$.
- 7. e_B and e_C are measured at the lead tips with the leads unconstrained. e_C must be zero or greater.
- 8. B1 maximum dimensions do not include dambar protrusions. Dambar protrusions shall not exceed 0.010 inch (0.25mm).
- 9. N is the maximum number of terminal positions.
- Corner leads (1, N, N/2 and N/2 + 1) for E8.3, E16.3, E18.3, E28.3, E42.6 will have a B1 dimension of 0.030 - 0.045 inch (0.76 -1.14mm).

E14.3 (JEDEC MS-001-AA ISSUE D) 14 LEAD DUAL-IN-LINE PLASTIC PACKAGE

	INC	HES	MILLIM		
SYMBOL	MIN	MAX	MIN	MAX	NOTES
A	-	0.210	-	5.33	4
A1	0.015	-	0.39	-	4
A2	0.115	0.195	2.93	4.95	-
В	0.014	0.022	0.356	0.558	-
B1	0.045	0.070	1.15	1.77	8
С	0.008	0.014	0.204	0.355	-
D	0.735	0.775	18.66	19.68	5
D1	0.005	-	0.13	-	5
E	0.300	0.325	7.62	8.25	6
E1	0.240	0.280	6.10	7.11	5
е	0.100	BSC	2.54	BSC	-
e _A	0.300	BSC	7.62	BSC	6
e _B	-	0.430	-	10.92	7
L	0.115	0.150	2.93	3.81	4
N	1	4	1	4	9

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Ceramic Dual-In-Line Frit Seal Packages (CERDIP)



NOTES:

- 1. Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark.
- 2. The maximum limits of lead dimensions b and c or M shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.
- 3. Dimensions b1 and c1 apply to lead base metal only. Dimension M applies to lead plating and finish thickness.
- 4. Corner leads (1, N, N/2, and N/2+1) may be configured with a partial lead paddle. For this configuration dimension b3 replaces dimension b2.
- 5. This dimension allows for off-center lid, meniscus, and glass overrun.
- 6. Dimension Q shall be measured from the seating plane to the base plane.
- 7. Measure dimension S1 at all four corners.
- 8. N is the maximum number of terminal positions.
- 9. Dimensioning and tolerancing per ANSI Y14.5M 1982.
- 10. Controlling dimension: INCH.

F14.3 MIL-STD-1835 GDIP1-T14 (D-1, CONFIGURATION A)
14 LEAD CERAMIC DUAL-IN-LINE FRIT SEAL PACKAGE

	INC	HES	MILLIM		
SYMBOL	MIN	MAX	MIN	MAX	NOTES
A	-	0.200	-	5.08	-
b	0.014	0.026	0.36	0.66	2
b1	0.014	0.023	0.36	0.58	3
b2	0.045	0.065	1.14	1.65	-
b3	0.023	0.045	0.58	1.14	4
с	0.008	0.018	0.20	0.46	2
c1	0.008	0.015	0.20	0.38	3
D	-	0.785	-	19.94	5
E	0.220	0.310	5.59	7.87	5
е	0.100	BSC	2.54	-	
eA	0.300	BSC	7.62 BSC		-
eA/2	0.150	BSC	3.81 BSC		-
L	0.125	0.200	3.18	5.08	-
Q	0.015	0.060	0.38	1.52	6
S1	0.005	-	0.13	-	7
α	90 ⁰	105 ⁰	90 ⁰	105 ⁰	-
aaa	-	0.015	-	0.38	-
bbb	-	0.030	-	0.76	-
CCC	-	0.010	-	0.25	-
М	-	0.0015	-	0.038	2, 3
N	1	4	1	4	8

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